TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (-MOSIV)

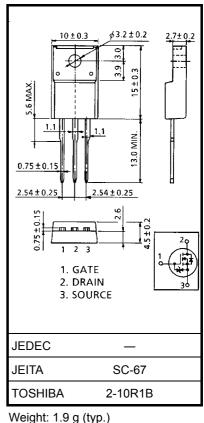
2SK4113

Switching Regulator Applications

- Low drain-source ON resistance: RDS (ON) = 2.0 (typ.)
- High forward transfer admittance: $|Y_{fs}| = 4.5 \text{ S} (typ.)$
- Low leakage current: $I_{DSS} = 100 \ \mu A (V_{DS} = 720 \ V)$
- Enhancement mode: $V_{th} = 2.0 \sim 4.0 \text{ V}$ (V_{DS} = 10 V, I_D = 1 mA)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	900	V	
Drain-gate voltage (F	t _{GS} = 20 kΩ)	V _{DGR}	900	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	Ι _D	5		
	Pulse (t = 1 ms) (Note 1)		15	A	
Drain power dissipati	on (Tc = 25°C)	PD	45	W	
Single pulse avalanc	ne energy (Note 2)	E _{AS}	595	mJ	
Avalanche current		I _{AR}	5	А	
Repetitive avalanche	energy (Note 3)	E _{AR}	4.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to case	R _{th (ch-c)}	2.78	°C/W	
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W	

Note 1: Ensure that the channel temperature does not exceed 150 .

Note 2: V_DD = 90 V, T_{ch} = 25 ^{\circ}C(Initial), L = 43.6 mH, I_{AR} = 5.0 A, R_G = 25 Ω

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

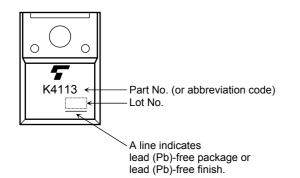
Electrical Characteristics (Ta = 25°C)

Char	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	$V_{GS}=\pm 25~V,~V_{DS}=0~V$	_	_	±10	μA
Gate-source brea	akdown voltage	V (BR) GSS	$I_G=\pm 10 \ \mu\text{A}, \ V_{DS}=0 \ V$	±30	_	_	V
Drain cut-off curr	ent	I _{DSS}	$V_{DS} = 720 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	_	100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	_	_	V
Gate threshold v	oltage	V _{th}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0		4.0	V
Drain-source ON	resistance	R _{DS (ON)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$	_	2.0	2.5	Ω
Forward transfer	admittance	Y _{fs}	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 3 \text{ A}$	2.0	4.5		S
Input capacitance		C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	1150	_	pF
Reverse transfer capacitance		C _{rss}			20		
Output capacitance		C _{oss}]		100	_	
Switching time	Rise time	tr	V_{GS} $0 V$ V_{GS} $0 V$ V_{GS} $0 V$ 0	_	30	_	• ns
	Turn-on time	t _{on}		_	70	_	
	Fall time	t _f		_	60	_	
	Turn-off time	t _{off}	Duty \leq 1%, t _w = 10 μ s		170		
Total gate charge		Qg		_	28	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	_	17	_	nC
Gate-drain charge		Q _{gd}]	_	11	_	

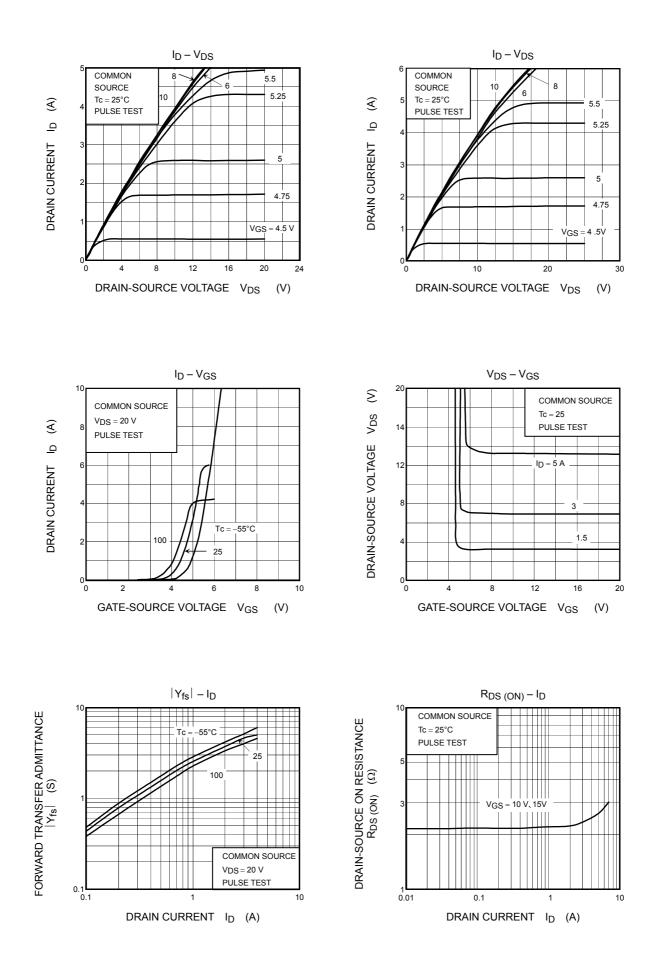
Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	—	_	_	5	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_		15	А
Forward voltage (diode)	V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V},$	_	900	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 100 A/μs	_	5.4	_	μC

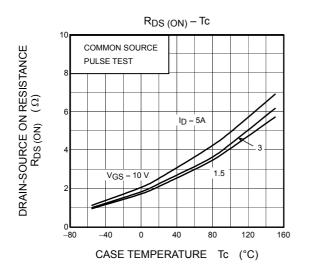
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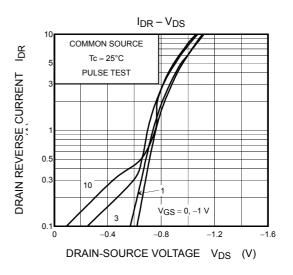


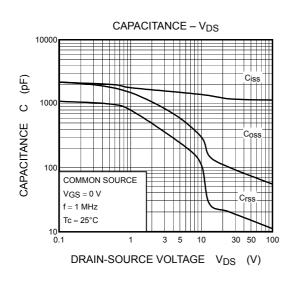
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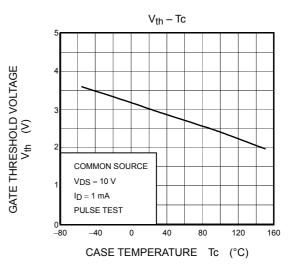


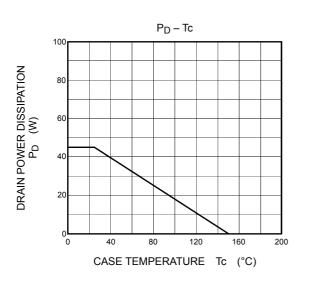
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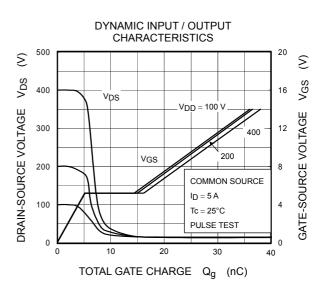


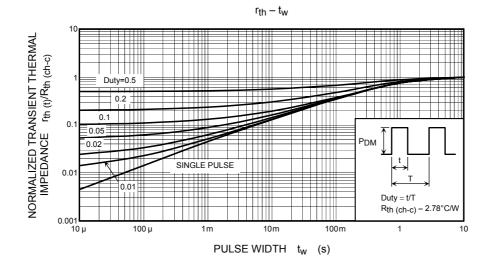


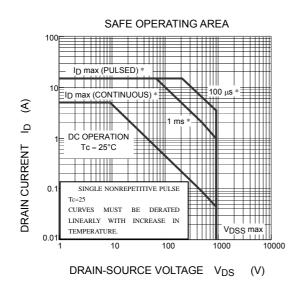


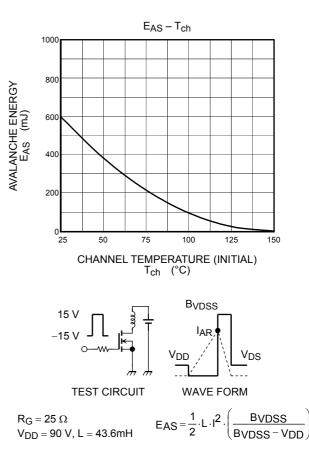












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